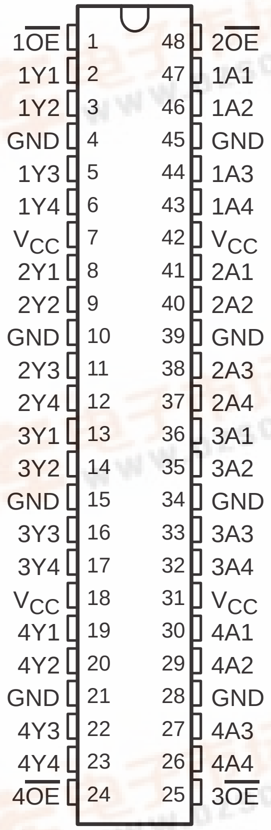
SN54ABTH16244, SN74ABTH16244
16-BIT BUFFERS/DRIVERS WITH 3-STATE OUTPUTS

SCBS677D – SEPTEMBER 1996 – REVISED MARCH 2000

- **Members of the Texas Instruments *Widebus*™ Family**
- **State-of-the-Art *EPIC*-II*B*™ BiCMOS Design Significantly Reduces Power Dissipation**
- **Latch-Up Performance Exceeds 500 mA Per JESD 17**
- **Typical V_{OLP} (Output Ground Bounce) <1 V at V_{CC} = 5 V, T_A = 25°C**
- **Distributed V_{CC} and GND Pins Minimize High-Speed Switching Noise**
- **Flow-Through Architecture Optimizes PCB Layout**
- **High-Drive Outputs (–32-mA I_{OH}, 64-mA I_{OL})**
- **Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors**
- **ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)**
- **Package Options Include Plastic Shrink Small-Outline (DL), Thin Shrink Small-Outline (DGG), Thin Very Small-Outline (DGV) Packages, and 380-mil Fine-Pitch Ceramic Flat (WD) Packages**

SN54ABTH16244 . . . WD PACKAGE
SN74ABTH16244 . . . DGG, DGV, OR DL PACKAGE
(TOP VIEW)



description

The ’ABTH16244 devices are 16-bit buffers and line drivers designed specifically to improve both the performance and density of 3-state memory address drivers, clock drivers, and bus-oriented receivers and transmitters. These devices can be used as four 4-bit buffers, two 8-bit buffers, or one 16-bit buffer. These devices provide true outputs and symmetrical active-low output-enable ($\overline{OE}$) inputs.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

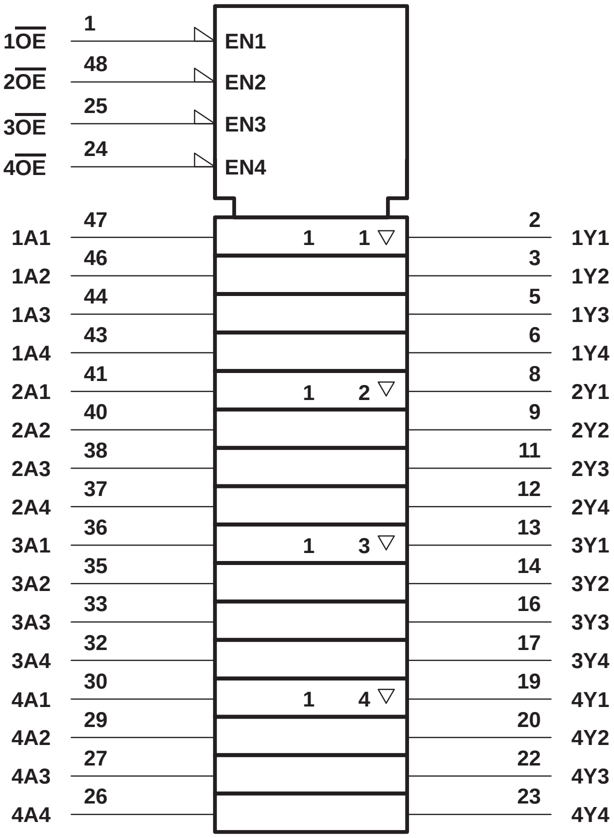
Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN54ABTH16244 is characterized for operation over the full military temperature range of –55°C to 125°C. The SN74ABTH16244 is characterized for operation from –40°C to 85°C.

FUNCTION TABLE
(each buffer)

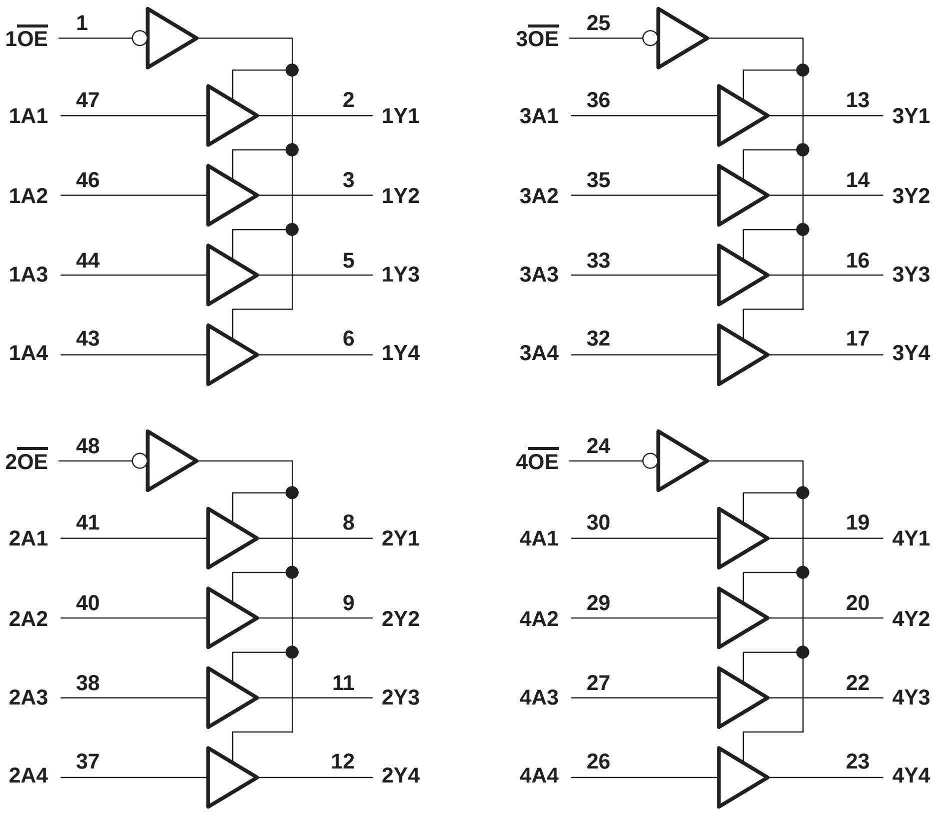
INPUTS		OUTPUT
$\overline{OE}$	A	Y
L	H	H
L	L	L
H	X	Z

logic symbol[†]



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V_{CC}		–0.5 V to 7 V
Input voltage range, V_I (see Note 1)		–0.5 V to 7 V
Voltage range applied to any output in the high or power-off state, V_O		–0.5 V to 5.5 V
Current into any output in the low state, I_O:	SN54ABTH16244	96 mA
	SN74ABTH16244	128 mA
Input clamp current, I_{IK} ($V_I < 0$)		–18 mA
Output clamp current, I_{OK} ($V_O < 0$)		–50 mA
Package thermal impedance, θ_{JA} (see Note 2):	DGG package	70°C/W
	DGV package	58°C/W
	DL package	63°C/W
Storage temperature range, T_{stg}		–65°C to 150°C

† Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.
2. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 3)

			SN54ABTH16244		SN74ABTH16244		UNIT
			MIN	MAX	MIN	MAX	
V_{CC}	Supply voltage		4.5	5.5	4.5	5.5	V
V_{IH}	High-level input voltage		2		2		V
V_{IL}	Low-level input voltage			0.8		0.8	V
V_I	Input voltage		0	V_{CC}	0	V_{CC}	V
I_{OH}	High-level output current			–24		–32	mA
I_{OL}	Low-level output current			48		64	mA
$\Delta t/\Delta v$	Input transition rise or fall rate	Outputs enabled		10		10	ns/V
T_A	Operating free-air temperature		–55	125	–40	85	°C

NOTE 3: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		$T_A = 25°C$			SN54ABTH16244		SN74ABTH16244		UNIT
			MIN	TYP†	MAX	MIN	MAX	MIN	MAX	
V_{IK}	$V_{CC} = 4.5$ V,	$I_I = –18$ mA			–1.2		–1.2		–1.2	V
V_{OH}	$V_{CC} = 4.5$ V,	$I_{OH} = –3$ mA	2.5			2.5		2.5		V
	$V_{CC} = 5$ V,	$I_{OH} = –3$ mA	3			3		3		
	$V_{CC} = 4.5$ V	$I_{OH} = –24$ mA	2			2				
		$I_{OH} = –32$ mA	2*					2		
V_{OL}	$V_{CC} = 4.5$ V	$I_{OL} = 48$ mA			0.55		0.55			V
		$I_{OL} = 64$ mA			0.55*				0.55	
V_{hys}				100						mV
I_I	$V_{CC} = 5.5$ V,	$V_I = V_{CC}$ or GND			±1		±1		±1	µA
$I_{I(hold)}$	$V_{CC} = 4.5$ V	$V_I = 0.8$ V	100			100		100		µA
		$V_I = 2$ V	–40			–40		–40		
I_{OZH}	$V_{CC} = 5.5$ V,	$V_O = 2.7$ V			10		10		10	µA
I_{OZL}	$V_{CC} = 5.5$ V,	$V_O = 0.5$ V			–10		–10		–10	µA
I_{off}	$V_{CC} = 0$,	V_I or $V_O \leq 4.5$ V			±100				±100	µA
I_{CEX}	$V_{CC} = 5.5$ V, $V_O = 5.5$ V	Outputs high			50		50		50	µA
I_O‡	$V_{CC} = 5.5$ V,	$V_O = 2.5$ V	–50	–100	–180	–50	–180	–50	–180	mA
I_{CC}	$V_{CC} = 5.5$ V, $I_O = 0$, $V_I = V_{CC}$ or GND	Outputs high			3		3		3	mA
		Outputs low			32		32		32	
		Outputs disabled			3		3		3	
ΔI_{CC}§	$V_{CC} = 5.5$ V, One input at 3.4 V, Other inputs at V_{CC} or GND				1.5		1.5		1.5	mA
C_i	$V_I = 2.5$ V or 0.5 V			3						pF
C_o	$V_O = 2.5$ V or 0.5 V			8						pF

* On products compliant to MIL-PRF-38535, this parameter does not apply.

† All typical values are at $V_{CC} = 5$ V.

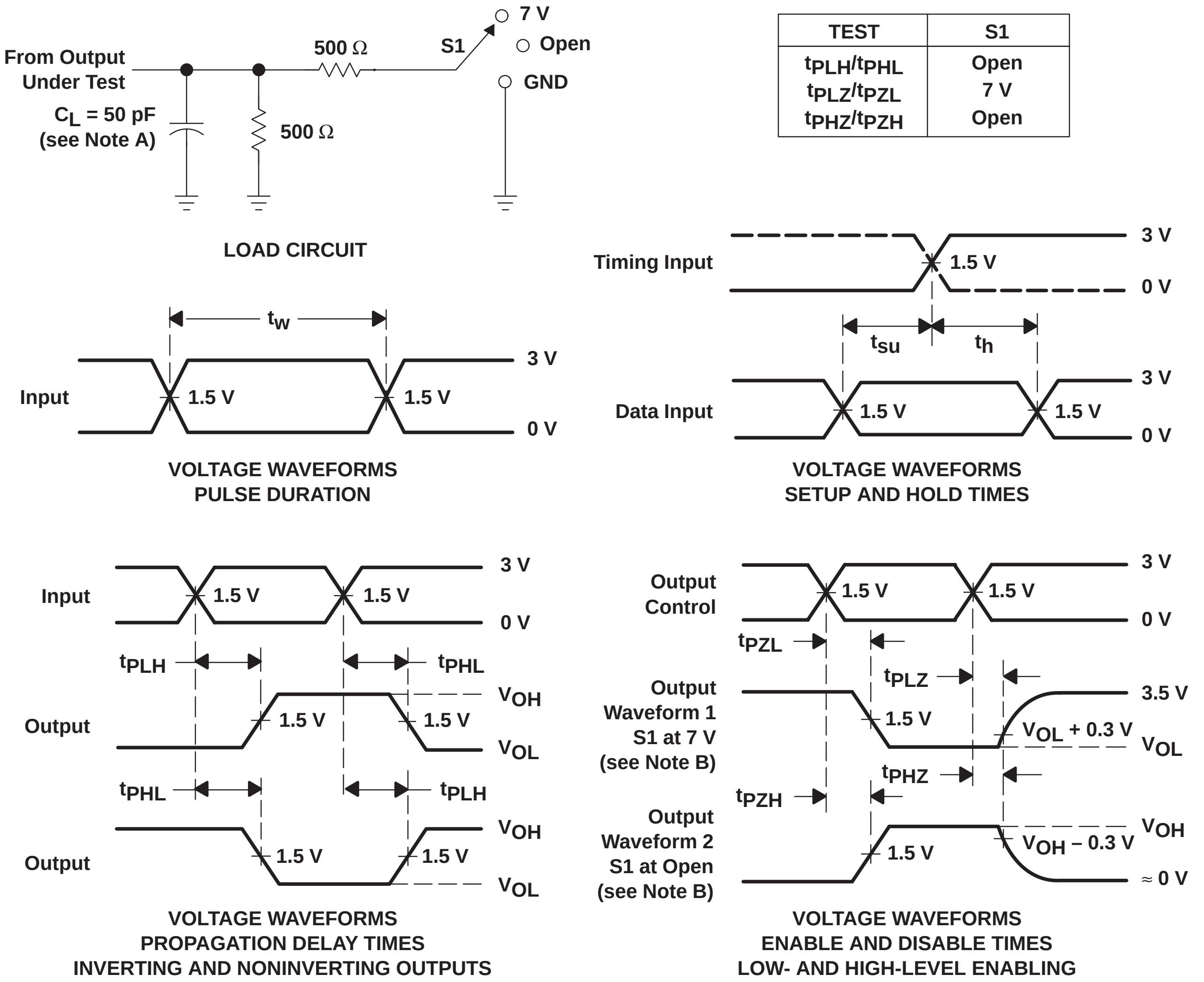
‡ Not more than one output should be tested at a time, and the duration of the test should not exceed one second.

§ This is the increase in supply current for each input that is at the specified TTL voltage level rather than V_{CC} or GND.

switching characteristics over recommended ranges of supply voltage and operating free-air temperature, C_L = 50 pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V_{CC} = 5 V, T_A = 25°C			SN54ABTH16244		SN74ABTH16244		UNIT
			MIN	TYP	MAX	MIN	MAX	MIN	MAX	
t_{PLH}	A	Y	1	2.3	3.2	0.7	3.6	1	3.5	ns
t_{PHL}			1	2.6	3.7	0.5	4.2	1	4.1	
t_{PZH}	$\overline{\text{OE}}$	Y	1	3	3.8	0.7	4.9	1	4.8	ns
t_{PZL}			1	3.2	4	0.9	5.3	1	4.8	
t_{PHZ}	$\overline{\text{OE}}$	Y	1	3.6	4.4	0.7	5.3	1	4.8	ns
t_{PLZ}			1	2.9	3.7	1	4.6	1	4.1	

PARAMETER MEASUREMENT INFORMATION



TEST	S1
t_{PLH}/t_{PHL}	Open
t_{PLZ}/t_{PZL}	7 V
t_{PHZ}/t_{PZH}	Open

NOTES:
- A. C_L includes probe and jig capacitance.
- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR ≤ 10 MHz, Z_O = 50 Ω, $t_r \leq 2.5$ ns, $t_f \leq 2.5$ ns.
- D. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

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